

**Preliminary Amendment**

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Title: DEVICE AND METHOD FOR TESTING INTEGRATED CIRCUITS

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**IN THE ABSTRACT**

Please replace the Abstract with the following rewritten paragraph:

~~Abstract~~

**DEVICE AND METHOD FOR TESTING INTEGRATED CIRCUITS**

**Abstract**

~~The~~A test device and method is disclosed. In one embodiment, the test device includes ~~according to the invention comprises~~ a precision signal generator (201) for generating a test signal, which generator is connected via a respective connecting line (409) to a respective input contact (211; 221, 231) intended for connection to an input of an integrated circuit, and at least one reference signal generator (401, 411) for generating a reference signal. Furthermore, at least one comparator unit (501, 511, 521) is provided for a respective input contact (211, 221, 231), said comparator unit being able to be operated in a test mode. In the test mode, the test signal is compared with the reference signal. The precision signal generator (201) is turned off by the comparator unit (501, 511, 521) if the test signal exceeds or falls below the reference signal.

~~{Figure 5}~~